

**Notice of References Cited**

Application/Control No.

09/840,711

Applicant(s)/Patent Under  
Reexamination  
VOYE ET AL.

Examiner

Lance W. Sealey

Art Unit

2671

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Description of the BYK-Gardner wave-scan DOI product, <a href="https://byk-gardnerusa.com">https://byk-gardnerusa.com</a> .
	V	
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